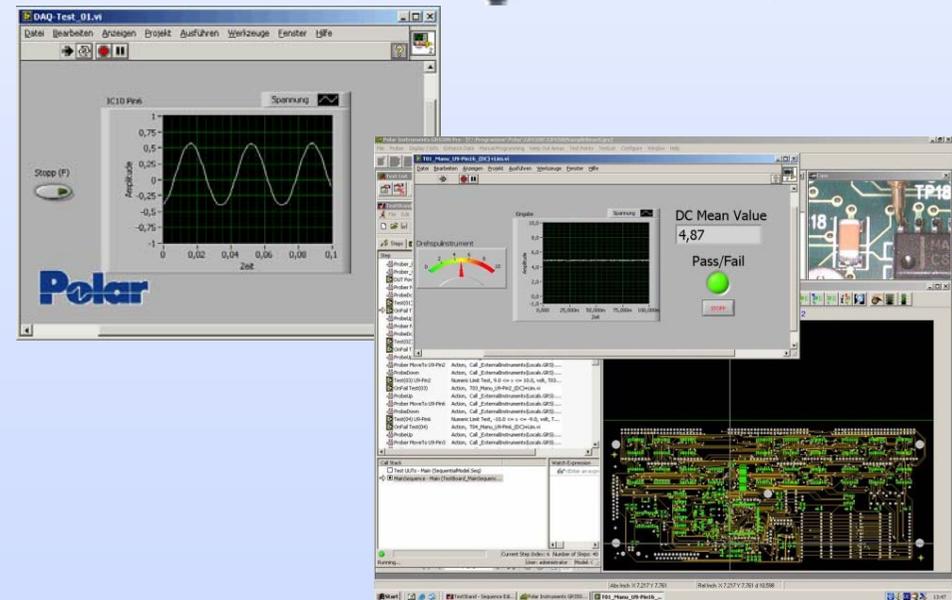
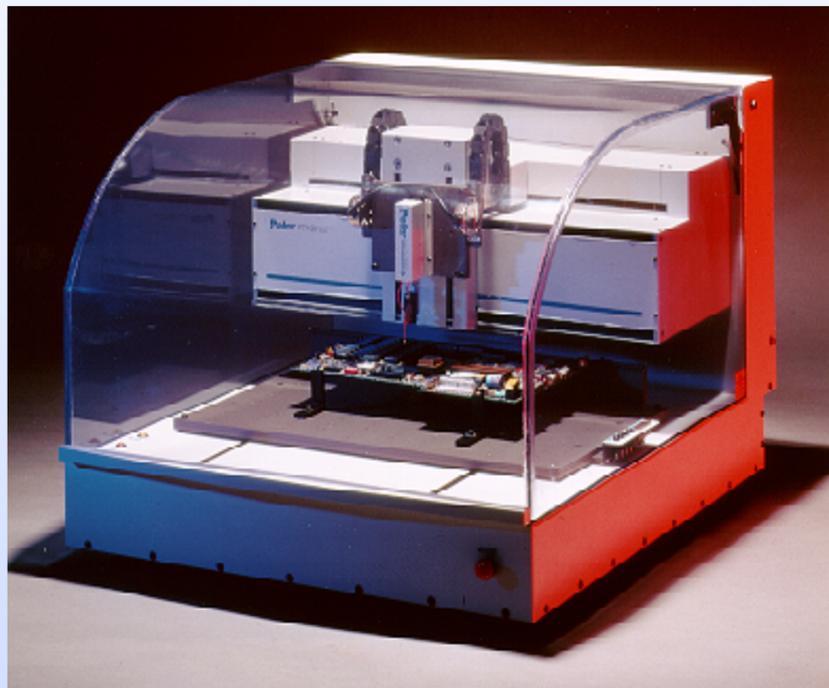
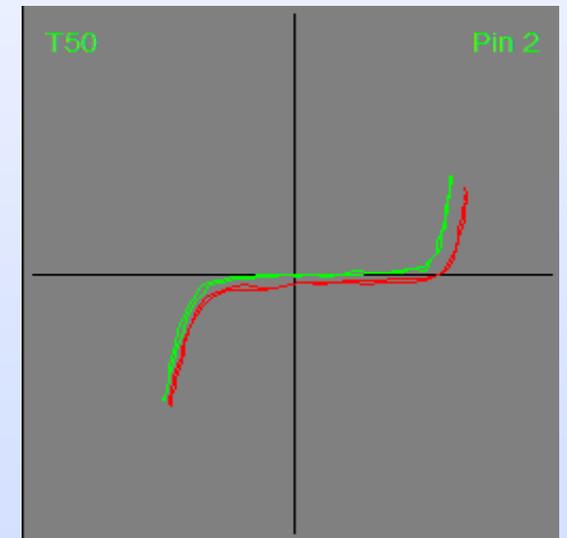
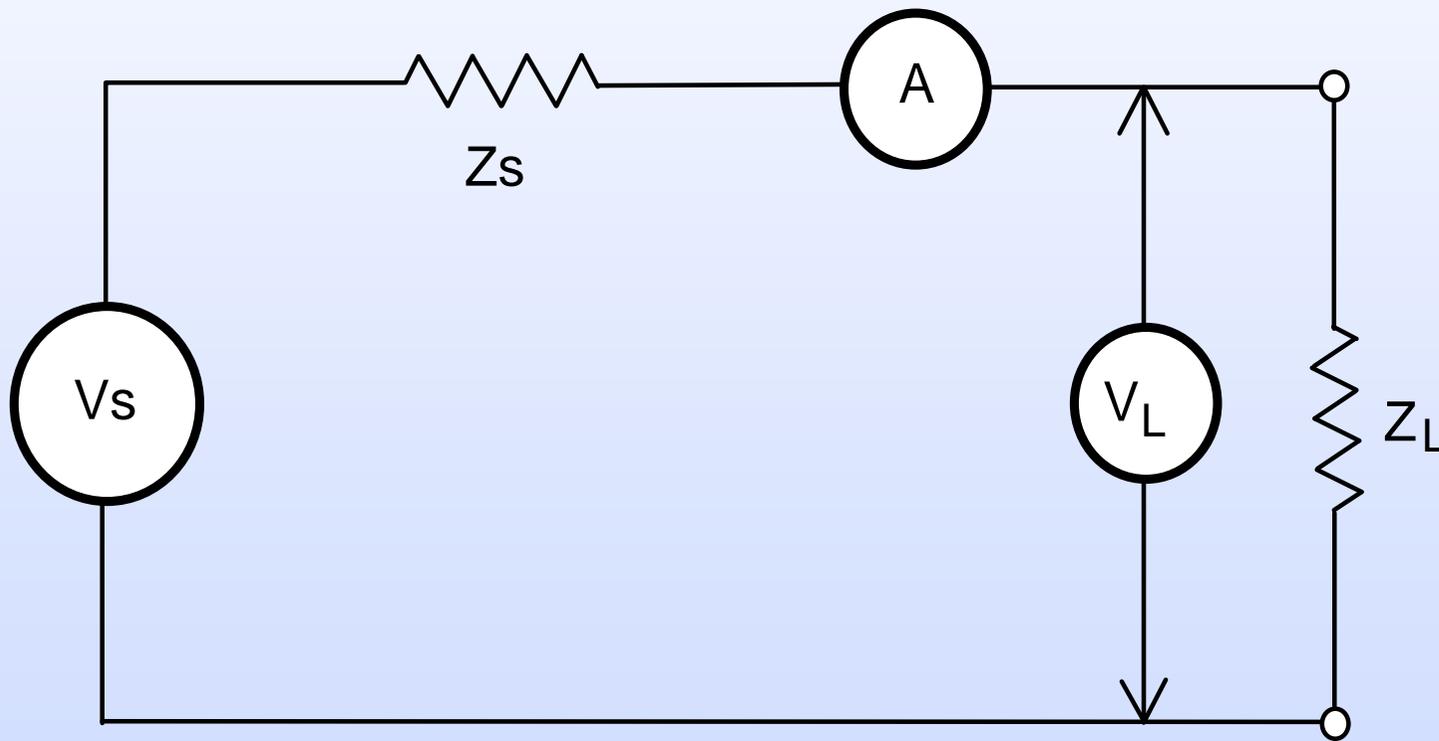


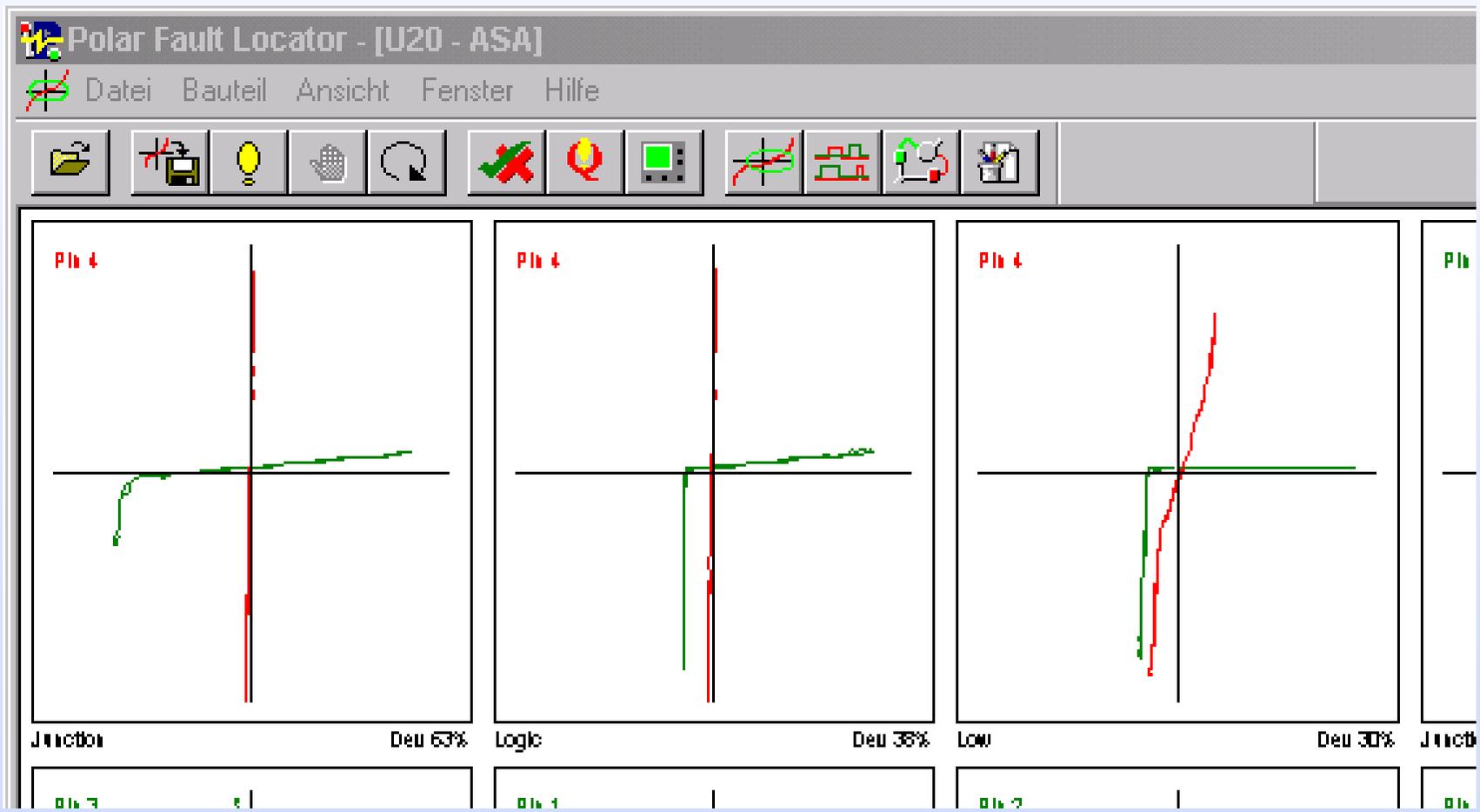
GRS550 Active Test Option



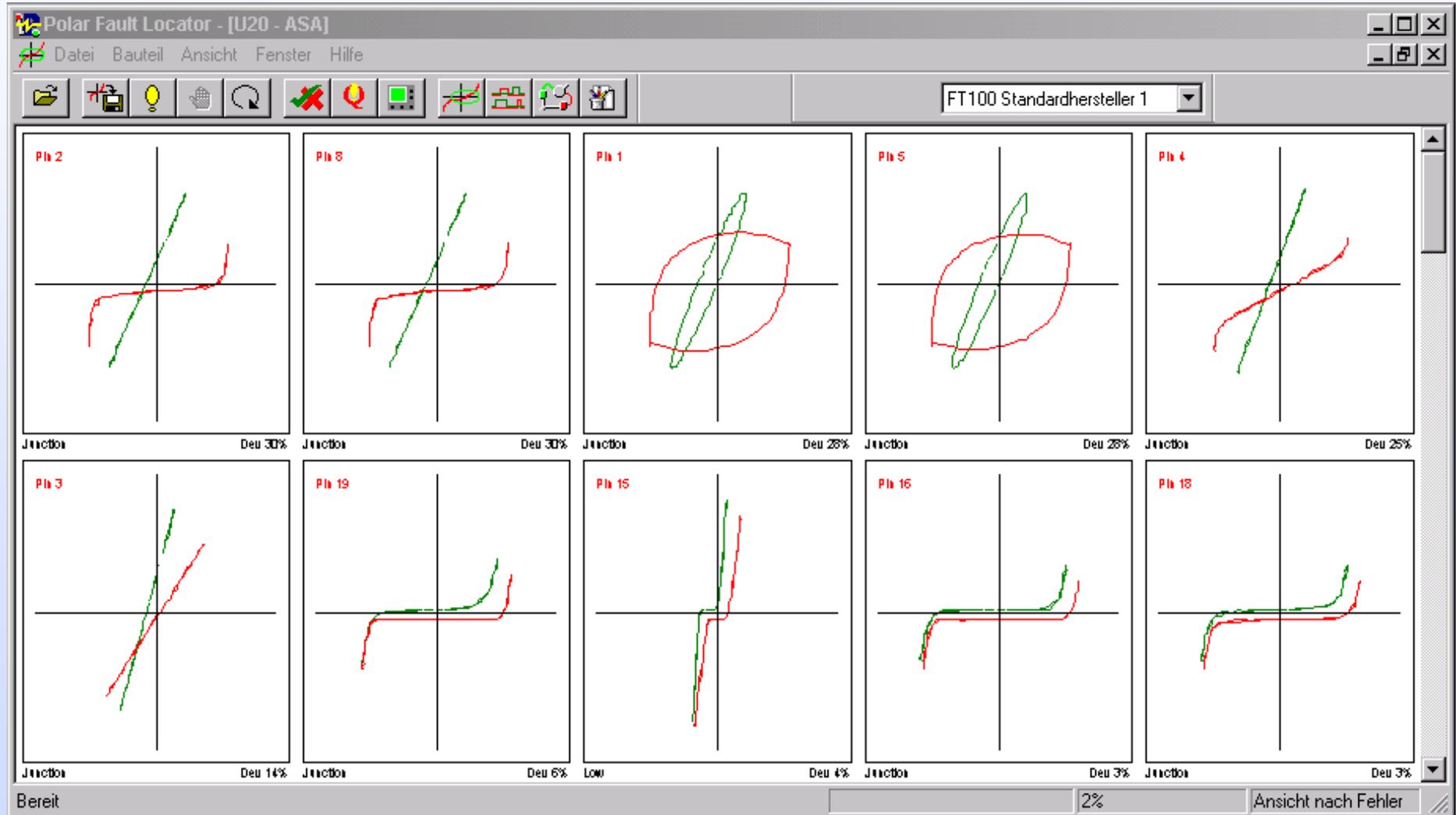
Analog Signature Analysis



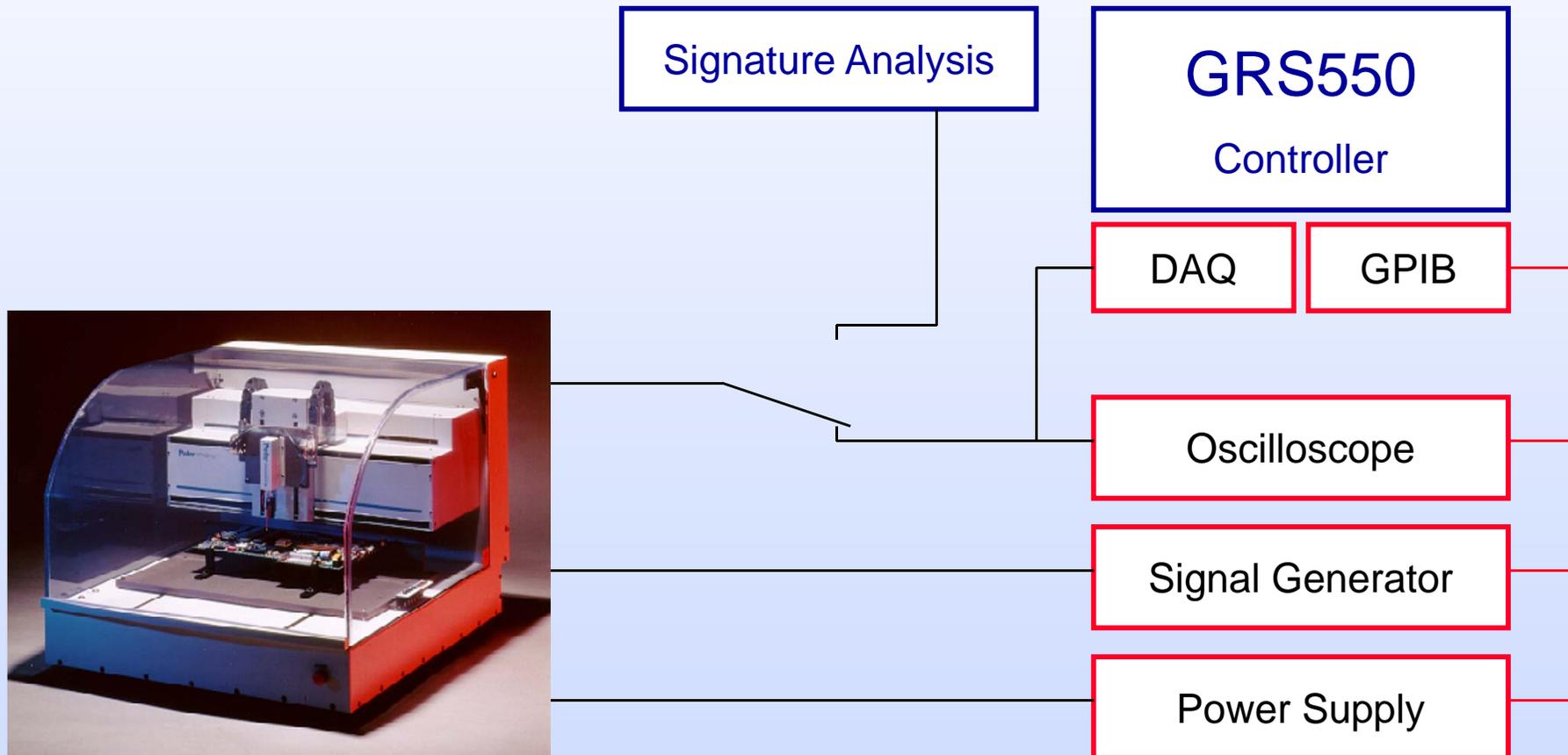
Typical ASA Faults



Typical ASA Faults



GRS550 Active Test Option

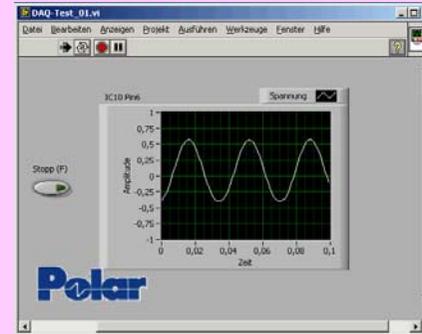


GRS550
Controller

GRS550
Software



National
Instruments
LabView



GPIB

USB

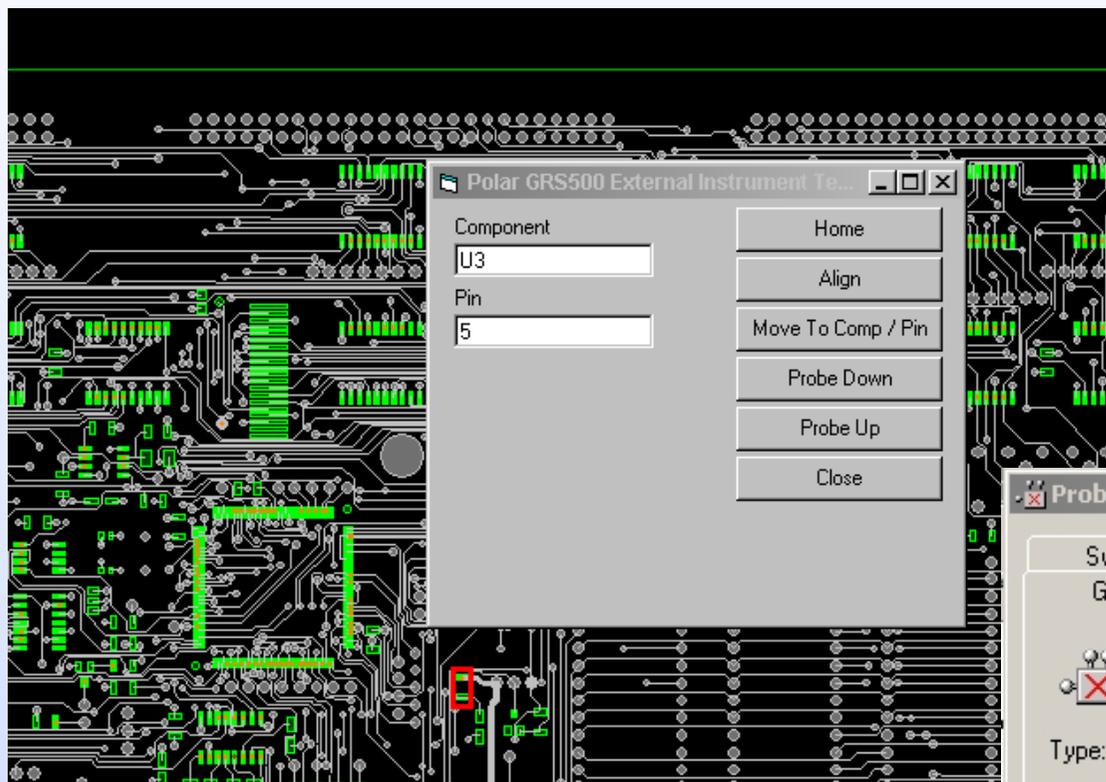
National
Instruments
TestStand

Step	Description	Flow Properties
Prober_Home	Action, Create ExternalInstruments; Call _Exte...	
Prober_Common4_Only	Action, Call _ExternalInstruments(Locals.GRS)...	
DUT PowerOn	Action, T00_Auto_DUT_Power-ON.vi	
Prober MoveTo U9-Pin16	Action, Call _ExternalInstruments(Locals.GRS)...	
ProbeDown	Action, Call _ExternalInstruments(Locals.GRS)...	
Test(01) U9-Pin16	Numeric Limit Test, 4.5 <= x <= 5.5, V, T01_Au...	Post Action
OnFail Test(01)	Action, T01_Manu_U9-Pin16_(DC)+Lim.vi	
ProberUp	Action, Call _ExternalInstruments(Locals.GRS)...	
Prober MoveTo U7-Pin4	Action, Call _ExternalInstruments(Locals.GRS)...	
ProbeDown	Action, Call _ExternalInstruments(Locals.GRS)...	
Test(02) U7-Pin4	Numeric Limit Test, 4.5 <= x <= 5.5, volt, T02_...	Post Action

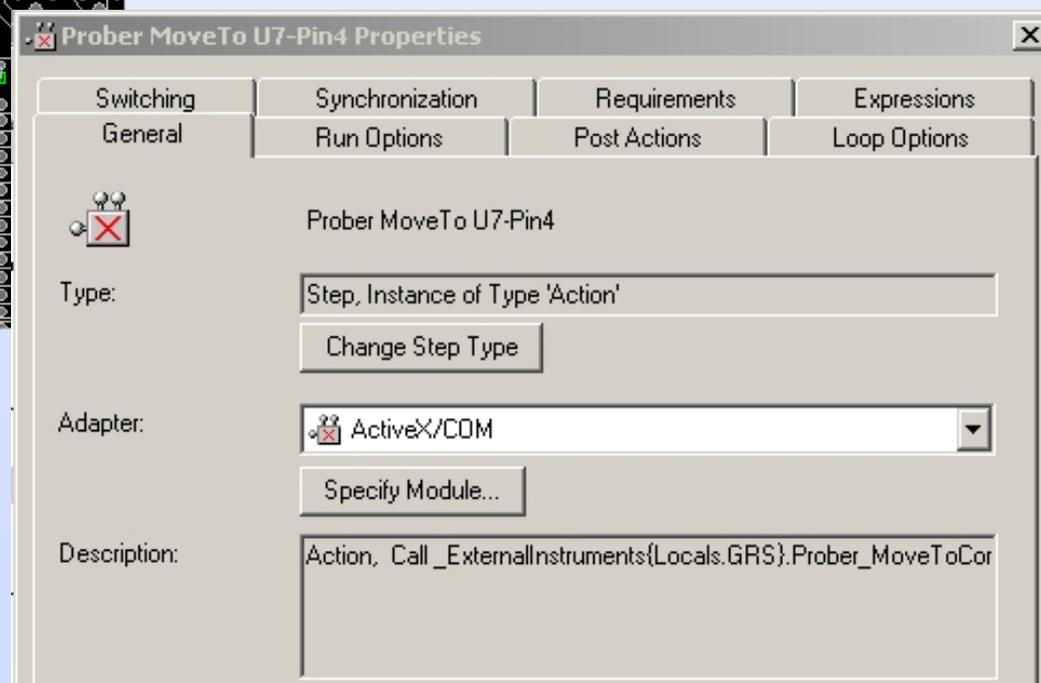
RS232

PCI

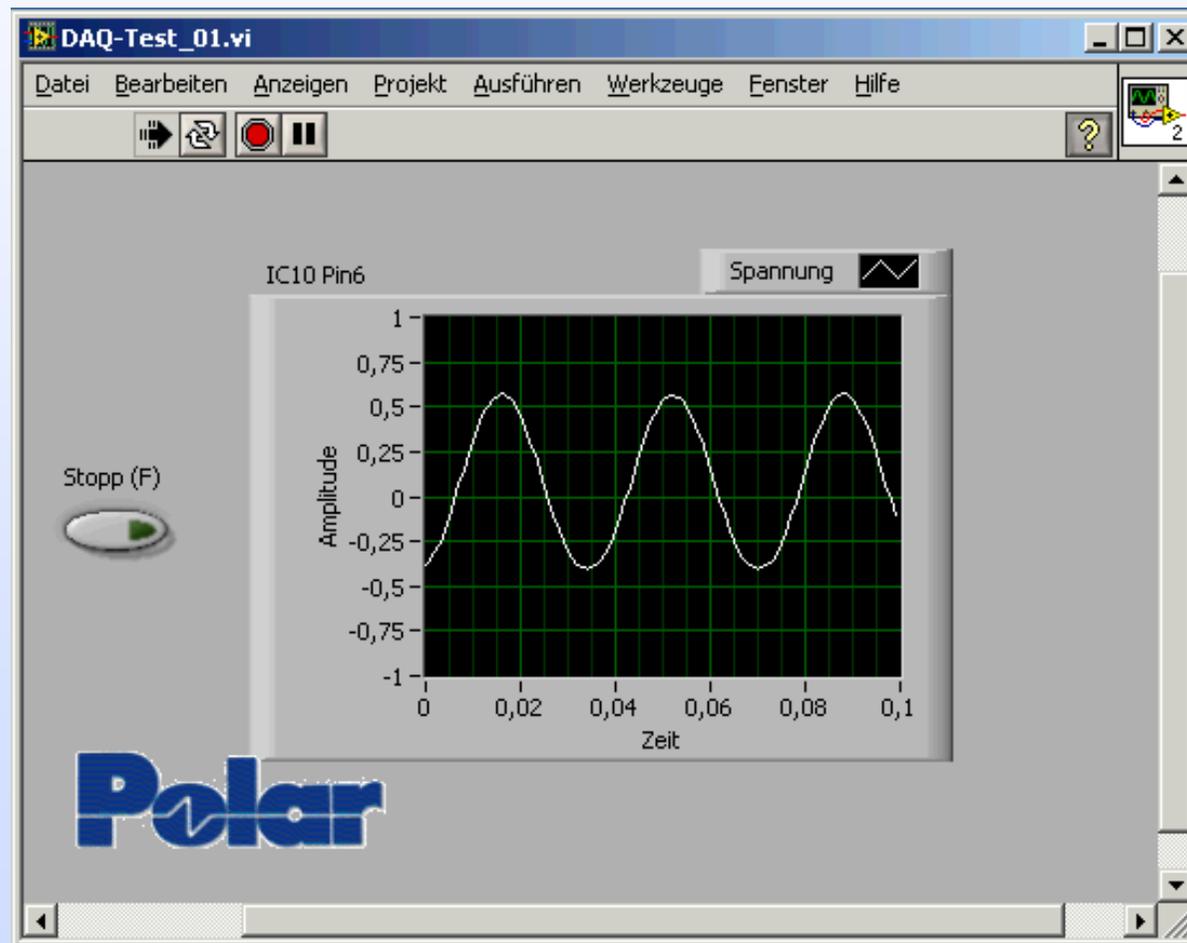
GRS550 External Instruments



NI TestStand



LabView



TestStand

C:\...\National Instruments_ELECTRONICA-06\TestStand\TestBoard_MainSequence.

Main Setup Cleanup Parameters Locals View: MainSequence

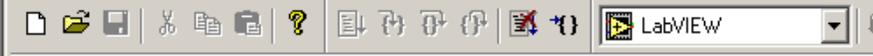
Step	Description	Flow Properties
 Prober_Home	Action, Create ExternalInstruments; Call _Exte...	
 Prober_Common4_Only	Action, Call _ExternalInstruments{Locals.GRS}....	
 DUT PowerOn	Action, T00_Auto_DUT_Power-ON.vi	
 Prober MoveTo U9-Pin16	Action, Call _ExternalInstruments{Locals.GRS}....	
 ProbeDown	Action, Call _ExternalInstruments{Locals.GRS}....	
 Test(01) U9-Pin16	Numeric Limit Test, $4.5 \leq x \leq 5.5$, V, T01_Au...	Post Action
 OnFail Test(01)	Action, T01_Manu_U9-Pin16_(DC)+Lim.vi	
 ProbeUp	Action, Call _ExternalInstruments{Locals.GRS}....	
 Prober MoveTo U7-Pin4	Action, Call _ExternalInstruments{Locals.GRS}....	
 ProbeDown	Action, Call _ExternalInstruments{Locals.GRS}....	
 Test(02) U7-Pin4	Numeric Limit Test, $4.5 \leq x \leq 5.5$, volt, T02_...	Post Action



Test List



TestStand - Sequence Editor [Running...]



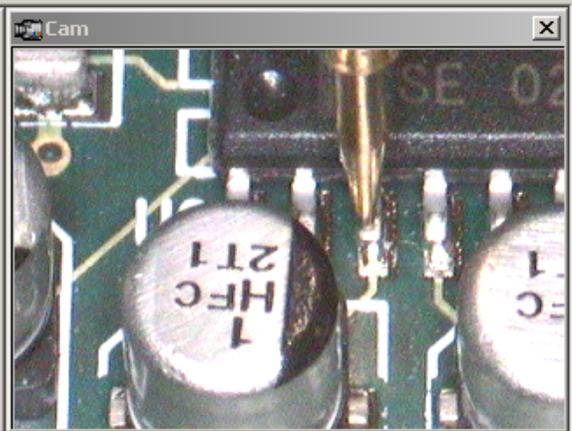
Steps **VRR** Context Report Threads: MainSequence - Main (TestBoard_MainSeque

Step	Description	Status
Prober MoveTo U9-Pin2	Action, Call _ExternalInstruments{Locals.GRS}....	Done
ProbeDown	Action, Call _ExternalInstruments{Locals.GRS}....	Done
Test(03) U9-Pin2	{9.4}, Numeric Limit Test, 9.0 <= x <= 10.0, v...	Passed
OnFail Test(03)	Action, T03_Manu_U9-Pin2 (DC)+Lim.vi	
ProbeUp	Action, Call _ExternalI...	
Prober MoveTo U9-Pin6	Action, Call _ExternalI...	
ProbeDown	Action, Call _ExternalI...	
Test(04) U9-Pin6	{-9.2}, Numeric Limit Te	
OnFail Test(04)	Action, T04_Manu_U9-	
ProbeUp	Action, Call _ExternalI...	
Prober MoveTo U9-Pin3	Action, Call _ExternalI...	
ProbeDown	Action, Call _ExternalI...	
Test(05) U9-Pin3	{3.2}, Numeric Limit Te	
OnFail Test(05)	Action, T05_Manu_U9-	
ProbeUp	Action, Call _ExternalI...	
Prober MoveTo U5-Pin82	Action, Call _ExternalI...	
ProbeDown	Action, Call _ExternalI...	
Test(06) U5-Pin82	Pass/Fail Test, T06_Au	
OnFail Test(06)	Action, T06_Manu_U5-	
ProbeUp	Action, Call _ExternalI...	
Prober MoveTo U9-Pin3	Action, Call _ExternalI...	
ProbeDown	Action, Call _ExternalI...	
Test(07) U5-Pin93	Pass/Fail Test, T07_Au	
OnFail_Test(07)	Action, T07_Manu_U5-	

Call Stack

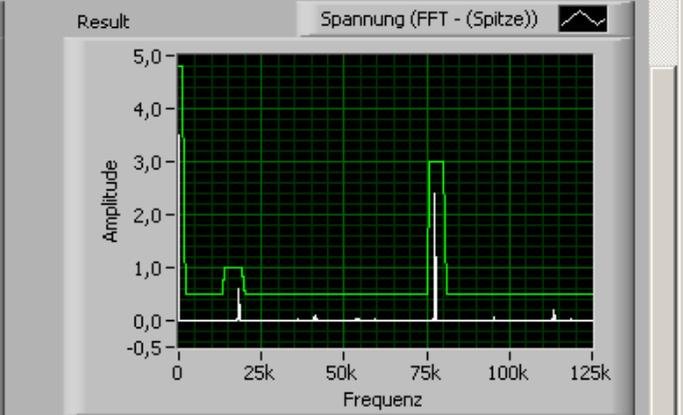
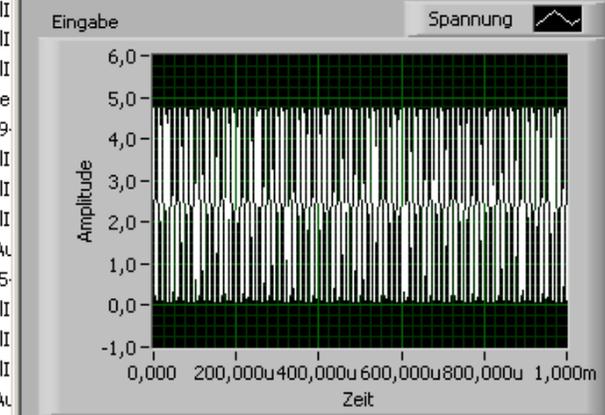
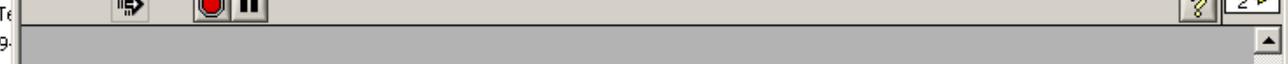
- Test UUTs - Main (SequentialModel.Seq)
- MainSequence - Main (TestBoard_MainSequenc...

Component Package



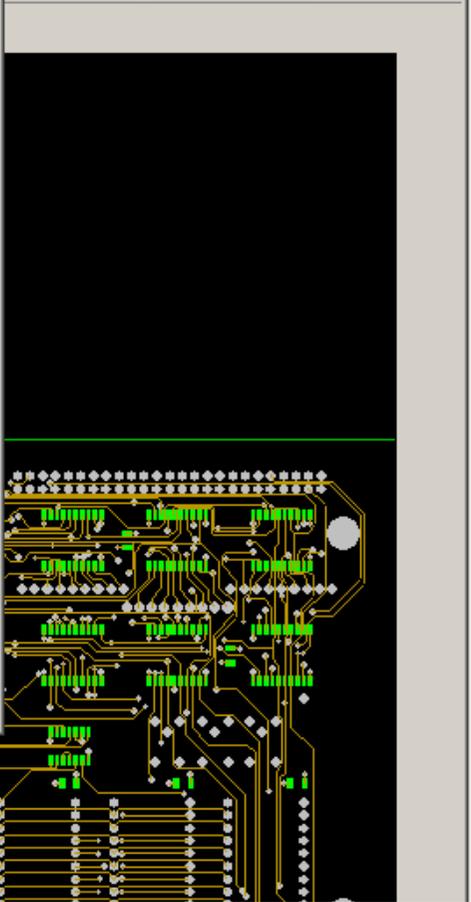
Board View

T07_Manu_U5-Pin93_(FDom)+Lim.vi



Pass/Fail

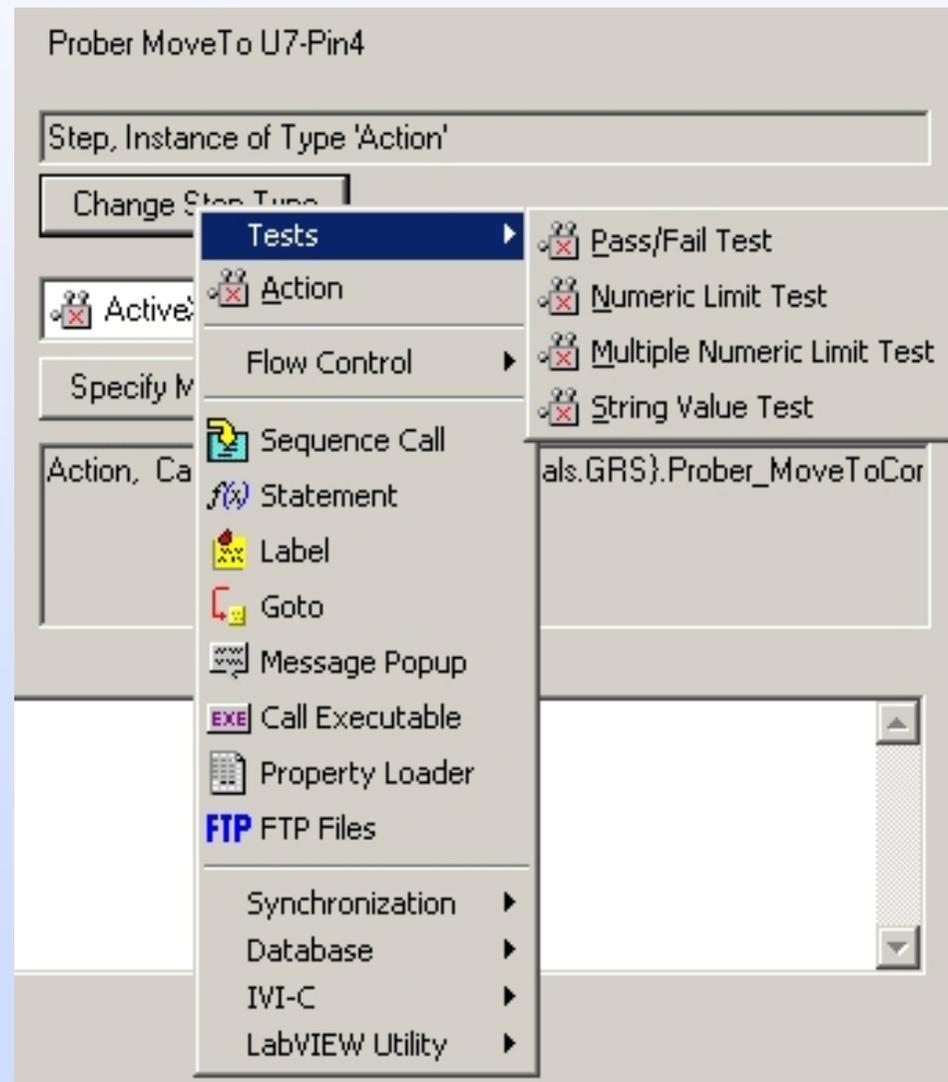
STOPP



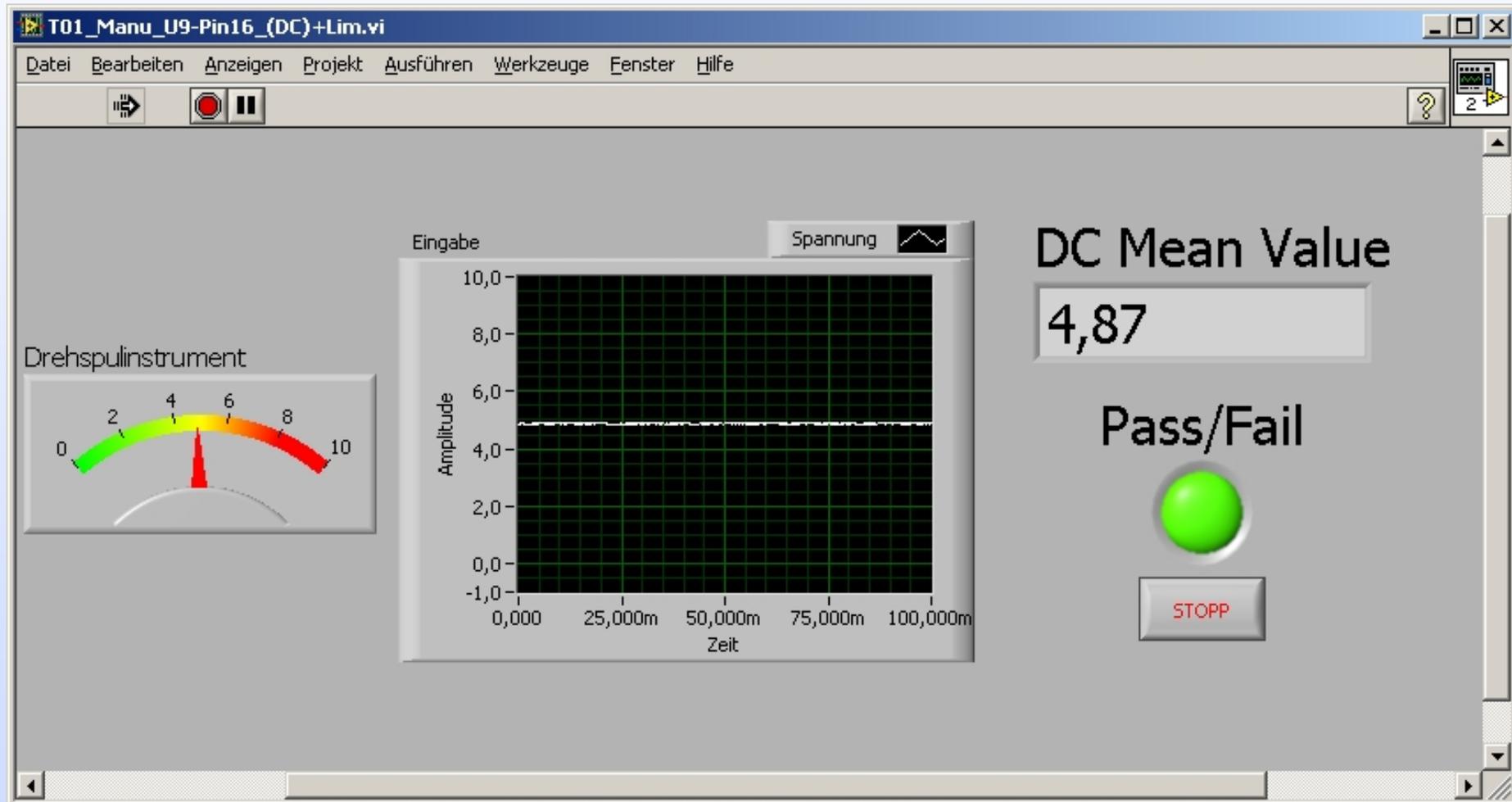
Active Test

- DC Measurement
- AC Measurement
- AC Waveform
- Tolerance Limits, Pass/Fail-Test
- FFT Spektrum Analysis
- Signal Generator
- Digital I/O Ports to control Device under Test
- Controlling additional instruments via GPIB, RS232, USB, PCI

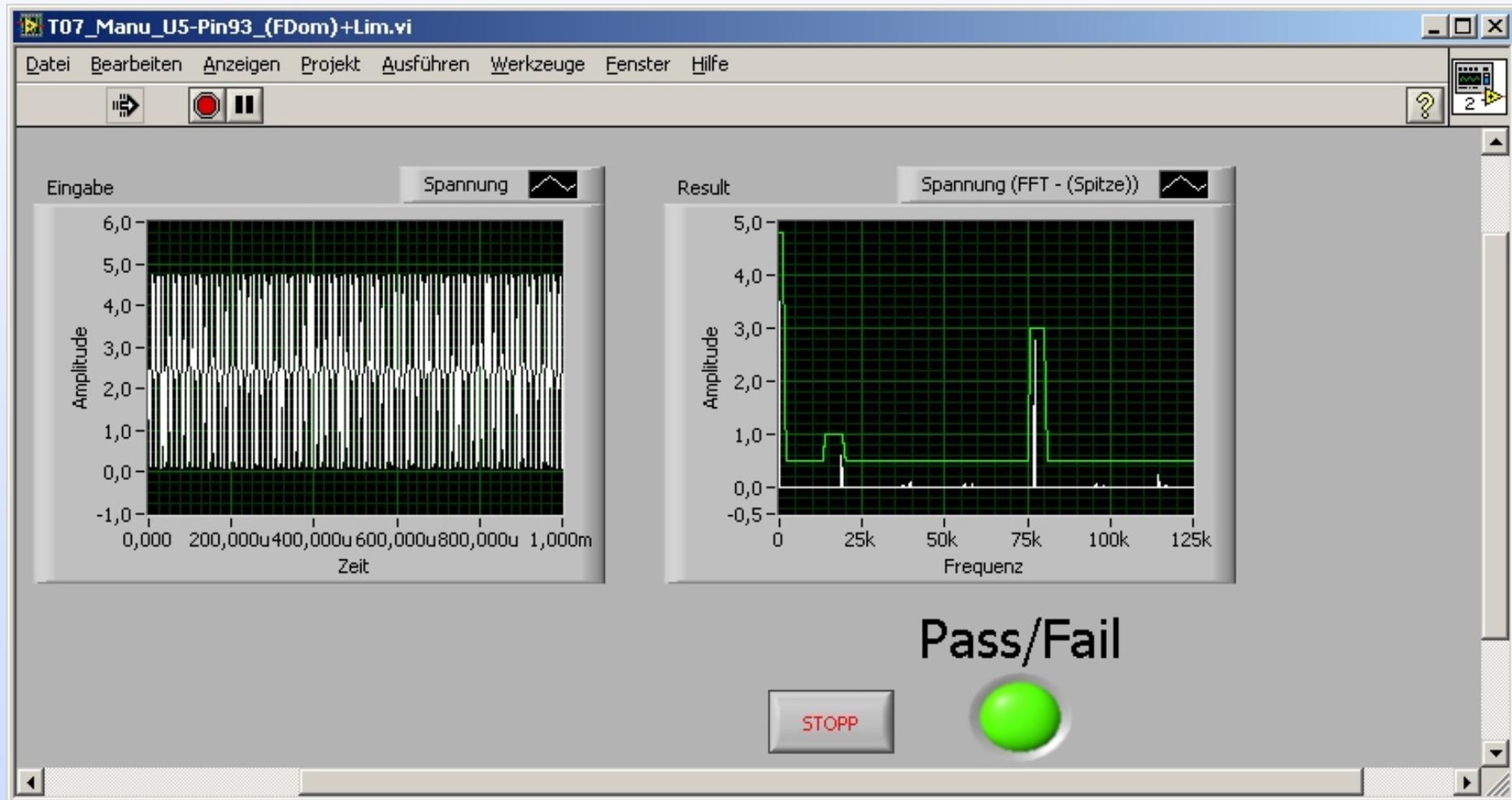
Active Test



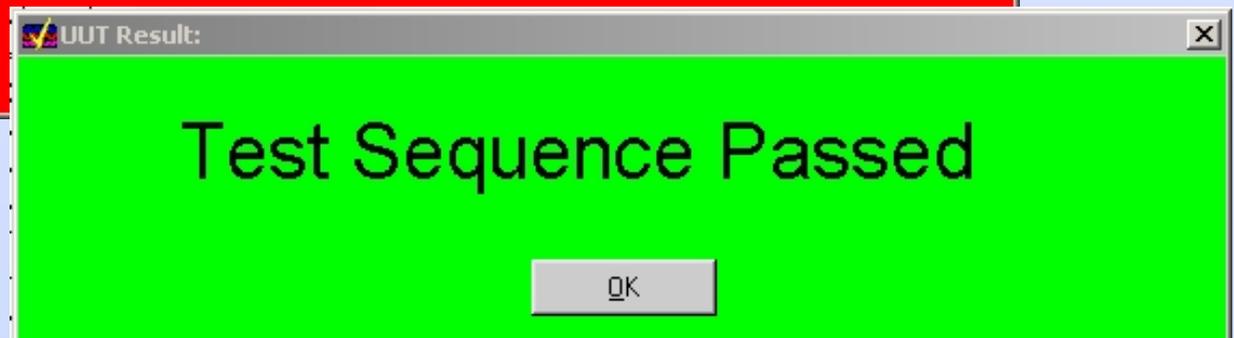
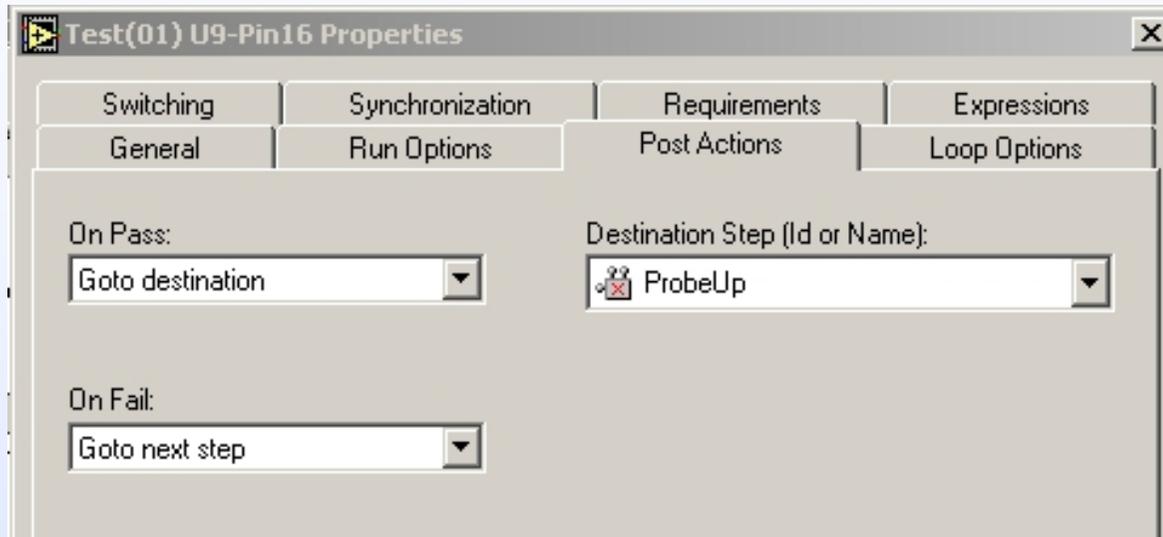
DC Measurement



FFT Analysis

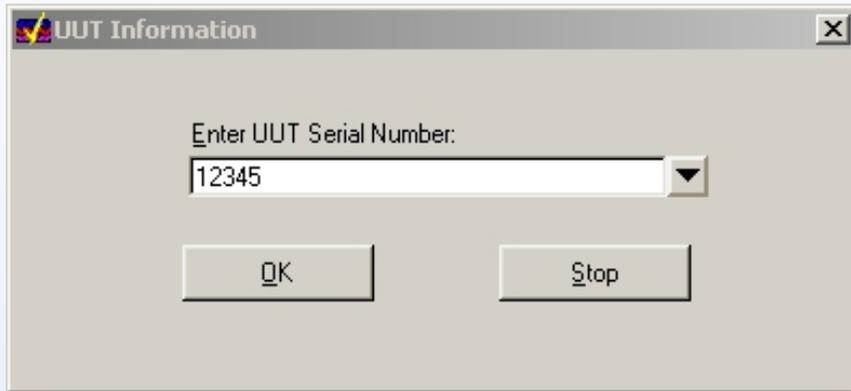


Conditional Jumps



Pass/Fail Test

Documentation



	Time	Operator	Execution Time	Number of Results	UUT Result
per 2006	13:03:51	administrator	98.1394582 seconds	7	Failed

Failure Chain		
Step	Sequence	Sequence File
Test(06) U5-Pin82	MainSequence	TestBoard_MainSequence.seq

Begin Sequence: MainSequence

(C:\Programme\National Instruments_ELECTRONICA-06\TestStand\TestBoard_MainSequence.seq)

Step	Status	Measurement	Units	Limits		
				Low Limit	High Limit	Comparison Type
Test(01) U9-Pin16	Passed	4.9 V		4.5	5.5	GELE(>= <=)
Test(02) U7-Pin4	Passed	5.0 volt		4.5	5.5	GELE(>= <=)
Test(03) U9-Pin2	Passed	9.4 volt		9.0	10.0	GELE(>= <=)
Test(04) U9-Pin6	Passed	-9.2 volt		-10.0	-9.0	GELE(>= <=)
Test(05) U9-Pin3	Passed	3.2 volt rms		2.5	3.5	GELE(>= <=)
Test(06) U5-Pin82	Failed					
Test(07) U5-Pin93	Failed					

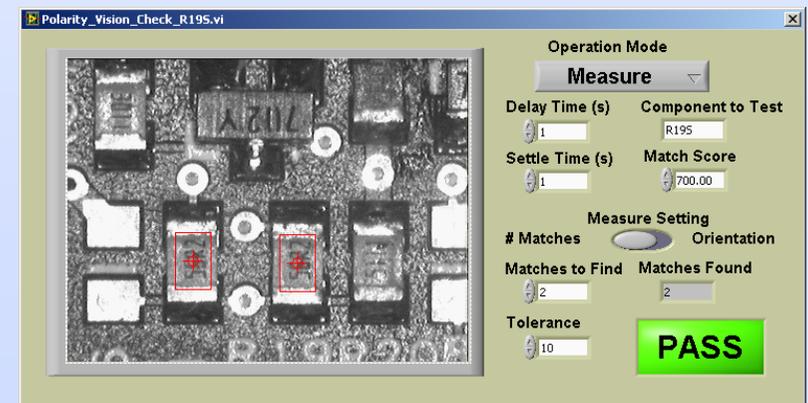
End Sequence: MainSequence

End UUT Report

ActiveVision

Add-On Module for ActiveTest

- uses powerful National Instruments „NI Vision“ Image processing software
- Integration of Vision-Tests in NI TestStand
- Checks for Presence
- Checks for Polarity
- Optical Character Recognition



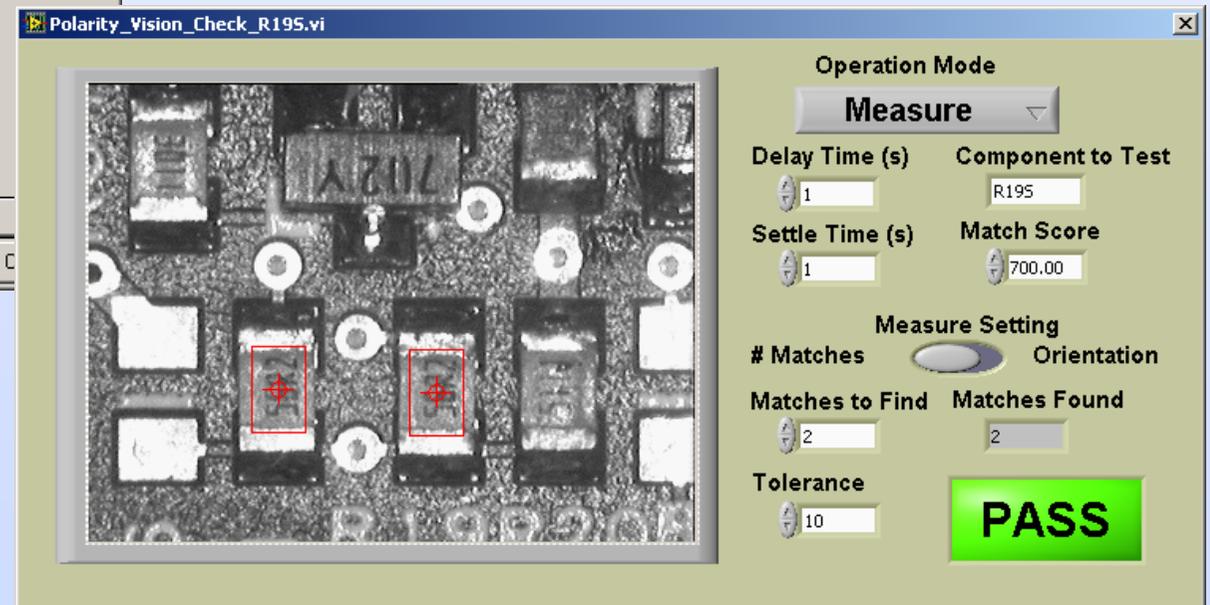
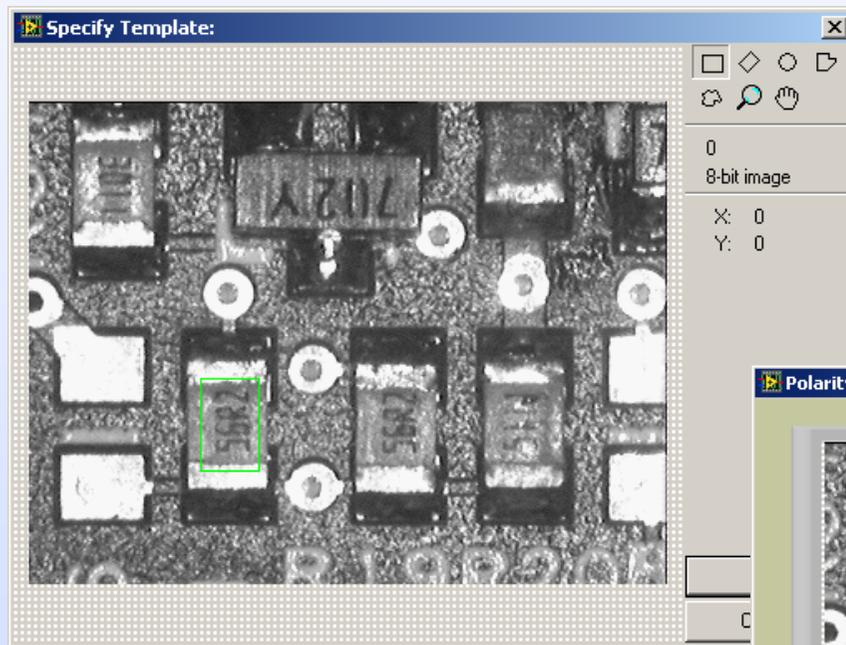
Active Vision Component Presence Detection

The screenshot shows a software window titled "Presence_Vision_Check_R19.vi". On the left, a grayscale image of a PCB is displayed with a red rectangular box highlighting a component. On the right, a control panel contains the following settings:

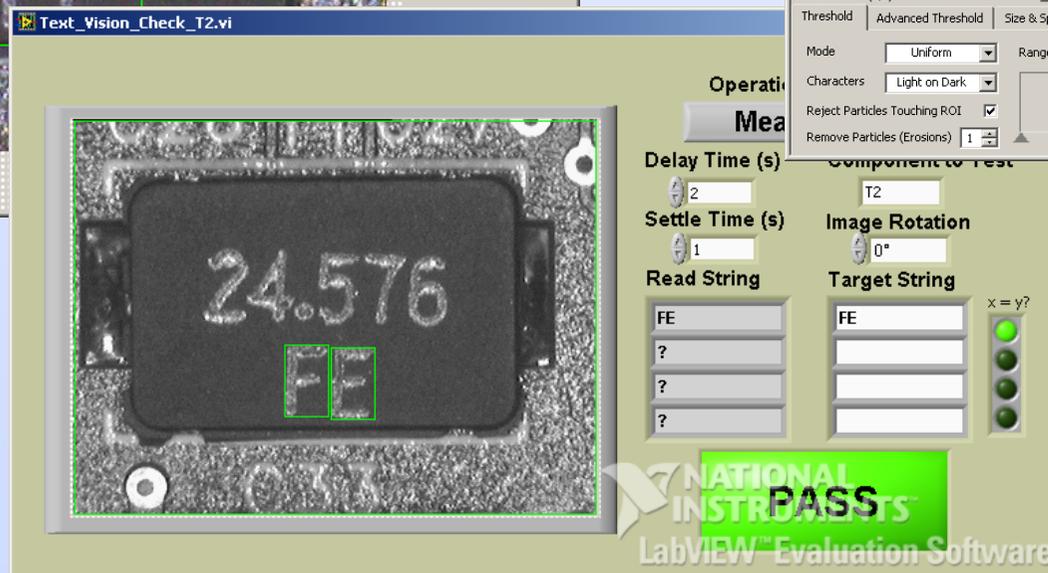
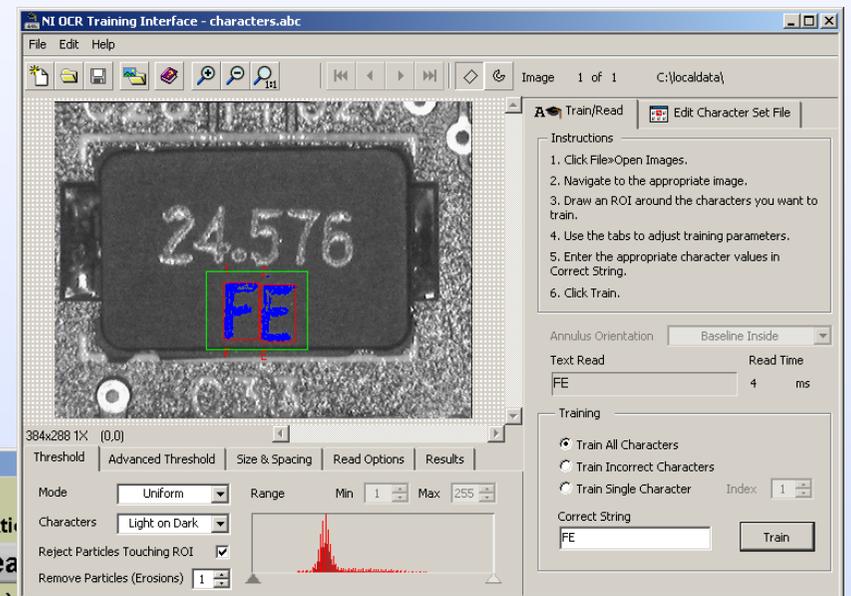
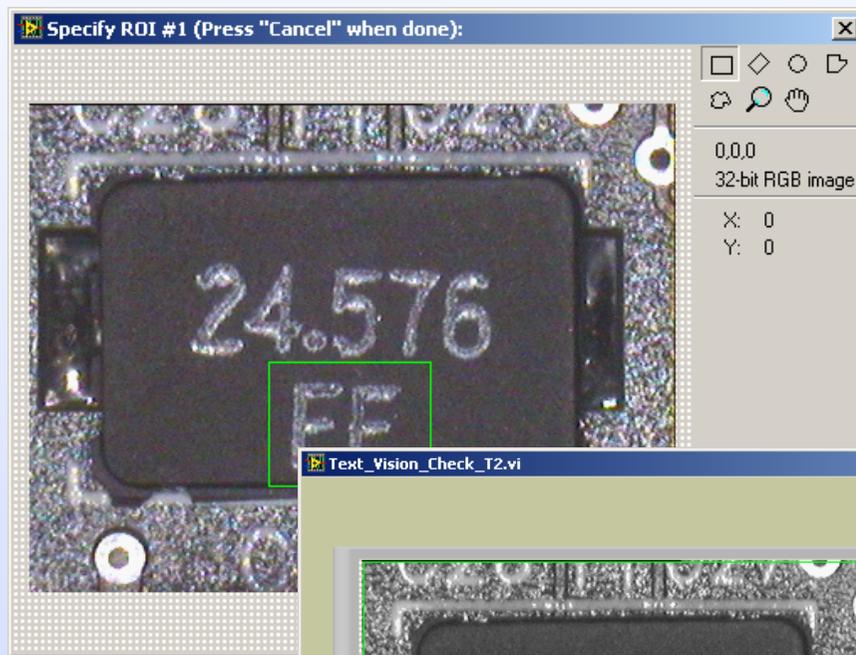
Operation Mode	
Measure	
Delay Time (s)	Component to Test
1	R19
Standard Variation 1	Difference
34.8314	4.8823
Standard Variation 2	Pass/Fail Level
39.7137	10
Settle Time (s)	Toleranz (%)
1	40

At the bottom of the control panel, a large red button displays the word "FAIL".

Active Vision Image Pattern Recognition



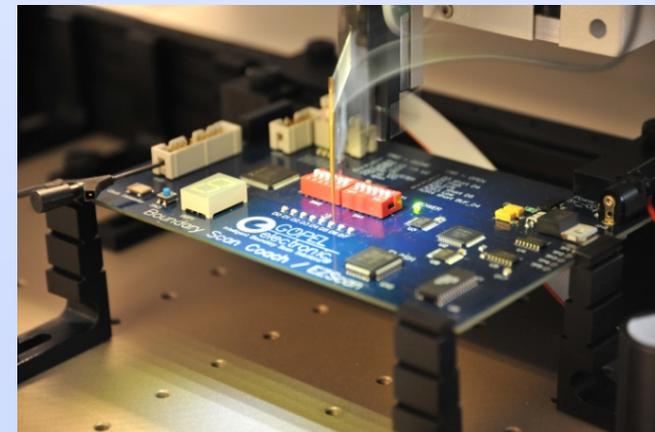
Active Vision Optical Character Recognition



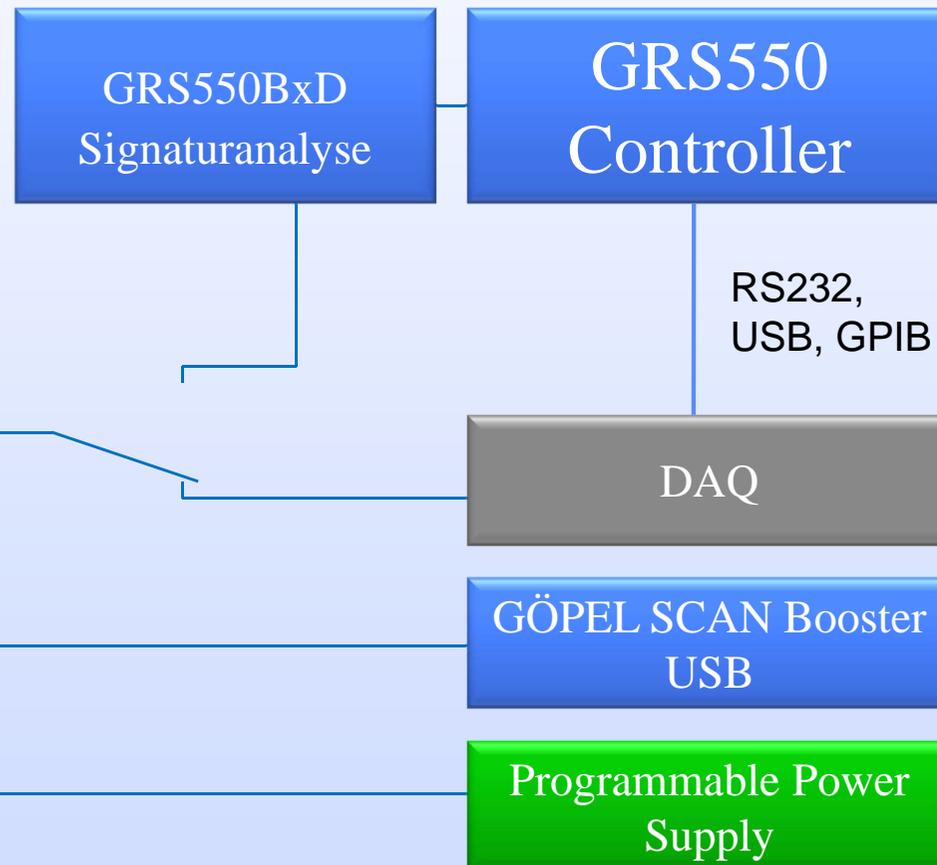
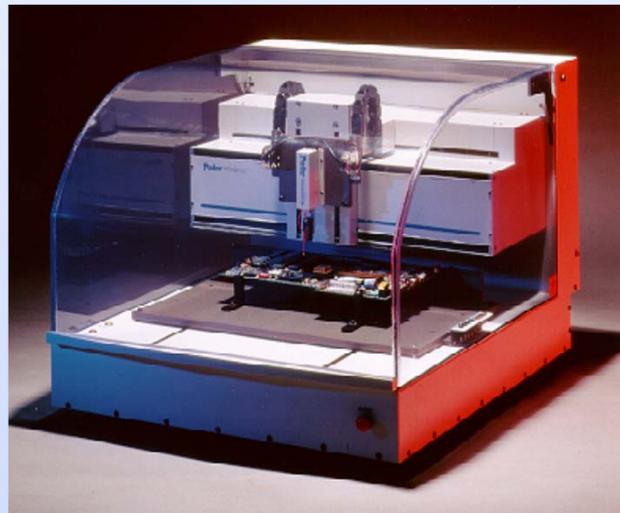
Boundary Scan

Add-On Module for ActiveTest

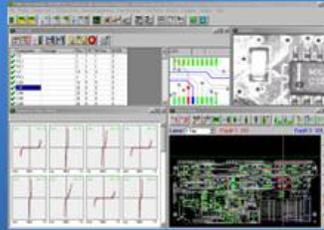
- Integrates GÖPEL Boundary Scan Hard- and Software
- Interfaces to NI TestStand
- Stimulates and checks nodes via GRS550 test pin



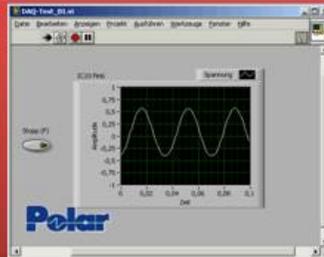
Boundary Scan Test



GRS500 Controller



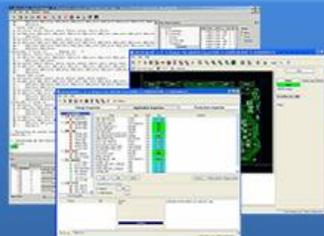
GRS500 Software
incl. CAD-Daten
Visualisierung



National Instruments
LabVIEW

Step	Description	File Properties
Prober_Home	Action, Create ExternalInstruments; Call_Elite...	
Prober_Connect_Only	Action, Call_ExternalInstruments(Locals.GRS)...	
OUT_PowerOn	Action, T02_Auto_OUT_PowerOn.vi	
Prober MoveTo U1-Pin16	Action, Call_ExternalInstruments(Locals.GRS)...	
ProberDown	Action, Call_ExternalInstruments(Locals.GRS)...	
Test(1) U1-Pin16	Numerical Unit Test, 4.5 <= x <= 5.5, Y, T02_Au...	Post Action
Test(1) U1-Pin16	Action, T02_Menu_U1-Pin16_IDCheck.vi	
ProberUp	Action, Call_ExternalInstruments(Locals.GRS)...	
Prober MoveTo U7-Pin4	Action, Call_ExternalInstruments(Locals.GRS)...	
ProberDown	Action, Call_ExternalInstruments(Locals.GRS)...	
Test(2) U7-Pin4	Numerical Unit Test, 4.5 <= x <= 5.5, volt, T02_...	Post Action

National Instruments
TestStand



GÖPEL CASCON
GALAXY Boundary Scan
Software

Boundary Scan Test

CASCON GALAXY 4.4.2d 1382 - [C:\Programme\CAS4WIN\Uuts\Boundary

File View Develop SCP Run Options Help

UUT: Boundary Scan Coach - EZScan_SV3

Test: Drive_D0_High_U1_23

Batch: ALL_ST_Flash

Serial Number: 594

02.07.2009 18:23:48 UUT: Boundary Scan Coach - EZScan

=====
 18:23:49 P A S S Elapsed Time 00:00:00.020
 =====

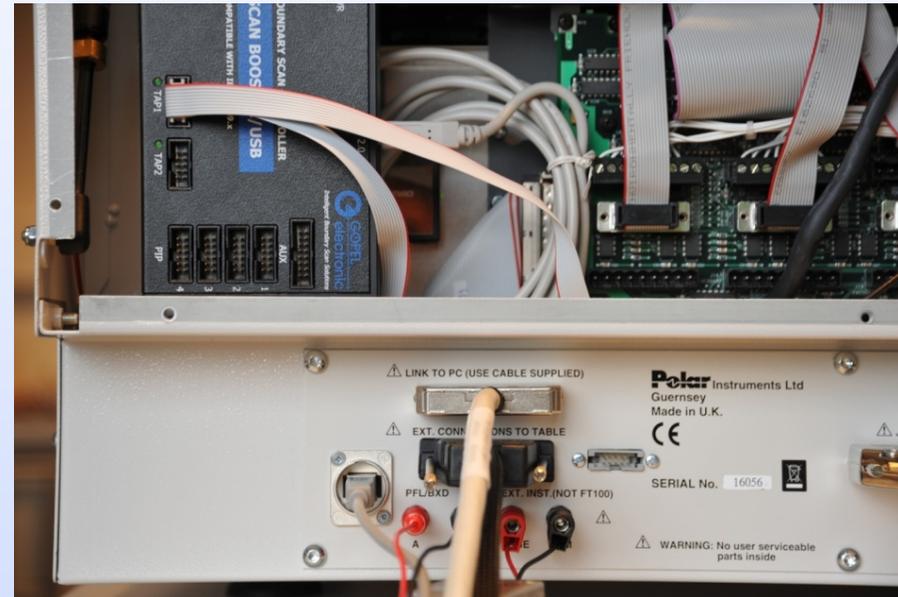
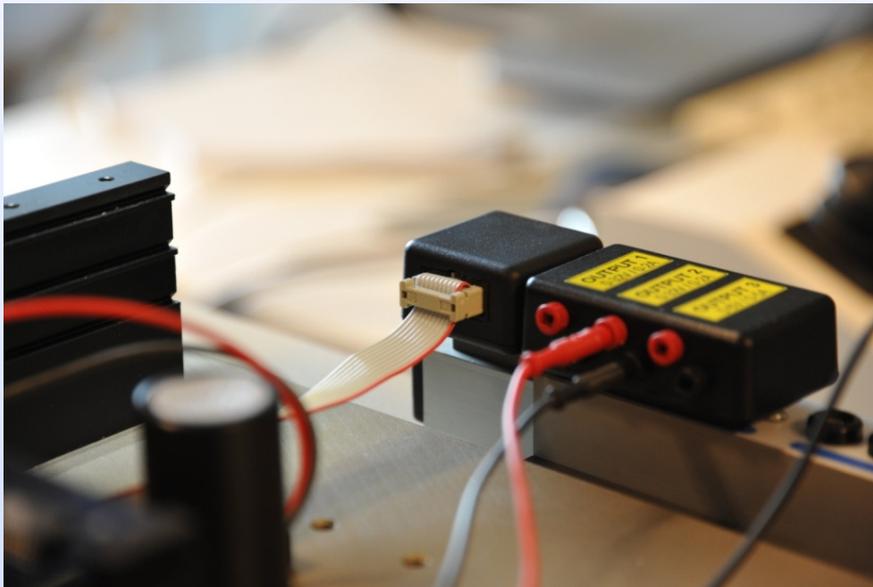
Number of DRShifts: 2

Board UUT: cmd> EXECUTE ready * TCK 30.00 MHz >> actual 16.13 MHz Testbyte ON 52H

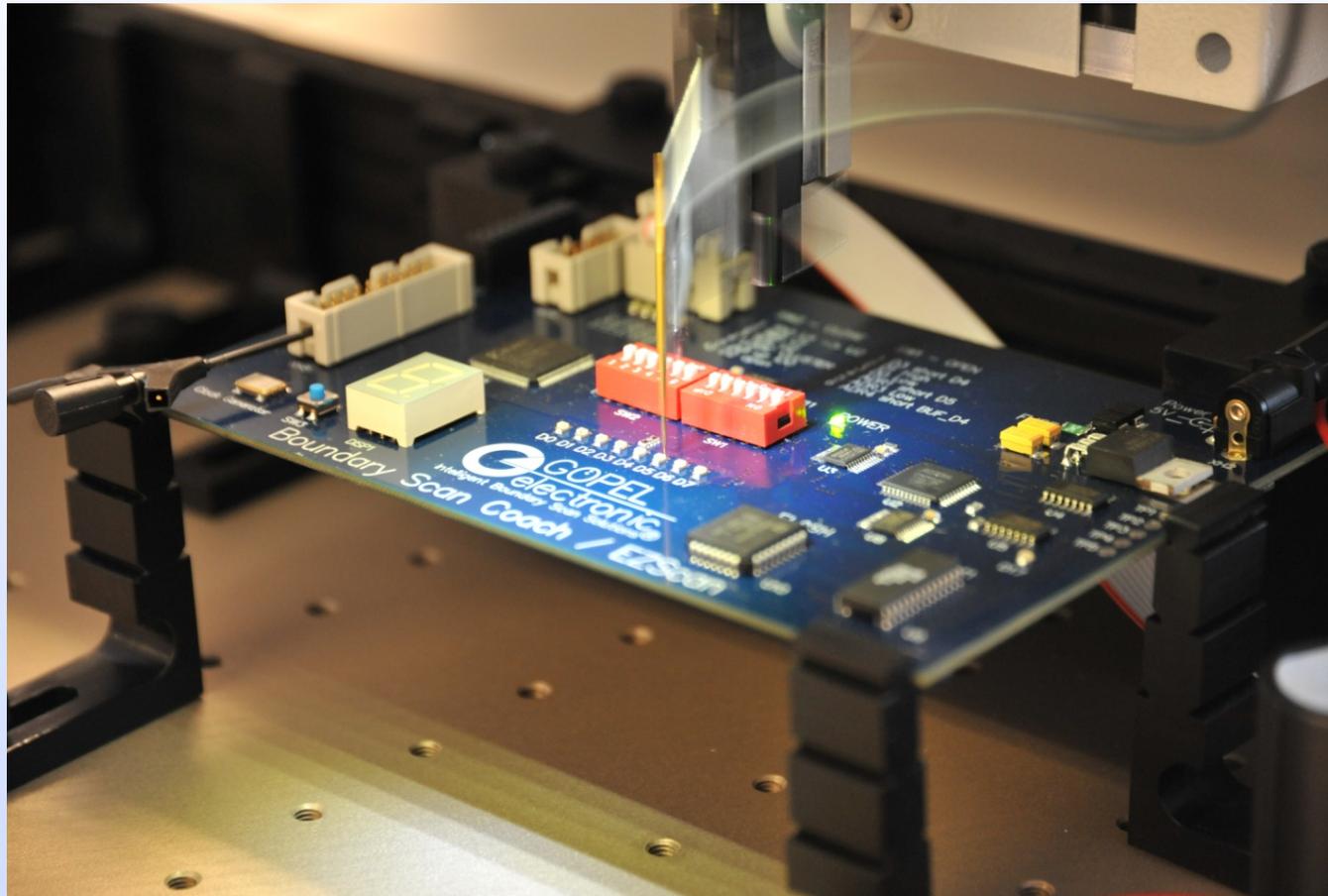
Name	Type	Build	State	Comment
Cluster_U11_DECP1	Cluster	Auto	pass	Cluster test for U11 / output is DECP1
Cluster_U11_DECP2	Cluster	Auto	pass	Cluster test for U11 / output is DECP2
Cluster_U4_A_B	Cluster	Auto	pass	Cluster test for U4A and U4B
Cluster_U4_C	Cluster	Auto	pass	Cluster test for U4C
Drive_D0_High_U1_23	Manually	Auto	pass	Controls LEDs D0 up to D7 with user interaction
Drive_D0_Low_U1_23	Manually	Auto	pass	Controls LEDs D0 up to D7 with user interaction
Drive_D1_High_U1_25	Manually	Auto	pass	Controls LEDs D0 up to D7 with user interaction
Drive_D1_Low_U1_25	Manually	Auto	pass	Controls LEDs D0 up to D7 with user interaction
Drive_D2_High_U1_27	Manually	Auto	pass	Controls LEDs D0 up to D7 with user interaction
Drive_D2_Low_U1_27	Manually	Auto	pass	Controls LEDs D0 up to D7 with user interaction
Drive_D3_High_U1_28	Manually	Auto	pass	Controls LEDs D0 up to D7 with user interaction
Drive_D3_Low_U1_28	Manually	Auto	pass	Controls LEDs D0 up to D7 with user interaction
Drive_D4_High_U1_29	Manually	Auto	pass	Controls LEDs D0 up to D7 with user interaction
Drive_D4_Low_U1_29	Manually	Auto	pass	Controls LEDs D0 up to D7 with user interaction
Drive_D5_High_U1_30	Manually	Auto	pass	Controls LEDs D0 up to D7 with user interaction
Drive_D5_Low_U1_30	Manually	Auto	pass	Controls LEDs D0 up to D7 with user interaction
Drive_D6_High_U1_32	Manually	Auto	pass	Controls LEDs D0 up to D7 with user interaction
Drive_D6_Low_U1_32	Manually	Auto	pass	Controls LEDs D0 up to D7 with user interaction
Drive_D7_High_U1_33	Manually	Auto	pass	Controls LEDs D0 up to D7 with user interaction
Drive_D7_Low_U1_33	Manually	Auto	pass	Controls LEDs D0 up to D7 with user interaction
Execute_Exe	Manually	Auto	pass	Starts an exe-file from CASLAN.
FLASH U10 (AMD)	FLASH	Auto	pass	Flash programming of U10 including Action Flow (Flash is from AMD)
FLASH U10 (ST)	FLASH	Auto	pass	Flash programming of U10 including Action Flow (Flash is from ST Micro)
Infrastructure	Infra structure	Auto	pass	Controls the function of the Testbus.
INTERCONNECTION	Interconnection	Auto	pass	Test of the Boundary scan connections
INTERCONNECTION_NO_U3	Interconnection	Auto	pass	Test of the Boundary scan connections (U3 is disabled)
LED Check Interaction	Manually	Auto	pass	Controls LEDs D0 up to D7 with user interaction
LED Check	Manually	Auto	pass	Controls LEDs D0 up to D7
RAM U9	RAM	Auto	pass	RAM test for U9 including Go / NoGo test
SVF U1_Clear	SVF (FPGA/PLD)	Auto	pass	SVF Programming of U1 (erases U1).
SVF U1_Program	SVF (FPGA/PLD)	Auto	pass	SVF Programming of U1 (programs U1).
SVF U2_Clear	SVF (FPGA/PLD)	Auto	pass	SVF Programming of U2 (erases U2).
SVF U2_Program	SVF (FPGA/PLD)	Auto	pass	SVF Programming of U2 (programs U2).
TAP_Reset	Manually	Auto	pass	
TCK Check Up	Manually	Auto	pass	version 1.2
Test_Clock	Manually	Auto	pass	Verifies the Q1 clock signal for H and L at U1 and U2. No frequency measurement.

Test Program Generation using GÖPEL CASCON GALAXY

Boundary Scan Test Integration in GRS550



Boundary Scan Test



Using the GRS550 and Boundary Scan Test to check logic levels.